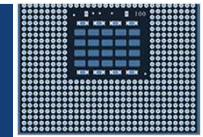




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490 N. McCarthy Blvd, #220  
Milpitas, CA 95035  
408-240-5700

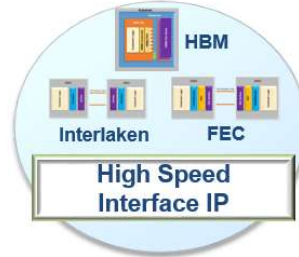
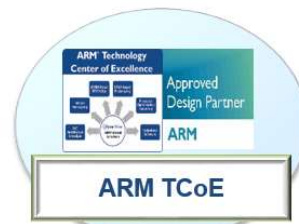
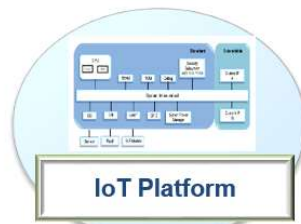
HQ



# High Volume Manufacturing Supply Chain Ecosystem for 2.5D HBM2 ASIC SiPs

© Open-Silicon, Inc.

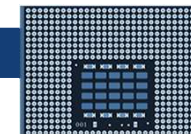
# Open-Silicon



**Asim Salim**

*VP Mfg. Operations*

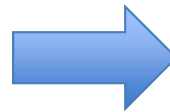
- 20+ experience in semiconductor operations engineering (product engineering, device physics, reliability, supply chain)
- Early adopter of SiPs – shipped >5M mobile graphics processors with DDR KGD memories in 1999



## The Need for 2.5D Integration with HBM (High Bandwidth Memories)

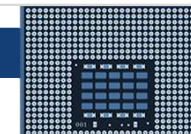
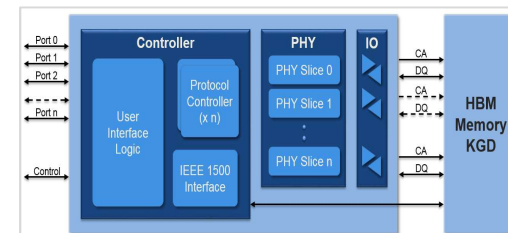
### Why 2.5D Has a Future → Memory Wall

- CPU performance is increasing 4x-8x compared to memory performance (processor can be idle for 50-75% idle times)
- Power is a big issue
  - *wide-IO to reduce frequency → lower power*
- IO space is limited → Integrate to reduce size
  - *Memory cannot become wider*
- Faster data
  - *USB, PCIe, SATA, all are faster now*
  - *Multiple interfaces vie for same DRAM*
  - *Larger on-chip storage is needed (video/graphics is the biggest contributor)*



### High Bandwidth Memory IP

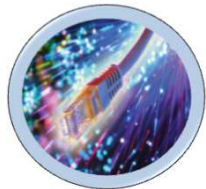
- *In-house design (Controller/PHY/IO)*
- *Leveraging 2.5D die2die “channel” experience from Avatar*
- *e.g. on Interposer interconnect electricals, ESD, DfT, etc.*
- *CMOS IO driver, 1GHz/2Gbps DDR with light output loading*
- *Electrically compatible with JEDEC HBM2 DRAM spec*
- *TSMC 16nm implementation*



# HBM Applications & Comparison



Data Centers



Networking



Artificial Intelligence



AR and VR

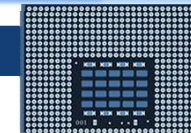


Cloud Computing



Neural Networks

	DDR4	GDDR5	HBM2
Bus Width (per chip)	16-bit	32-bit	1024-bit
Clock Speed	3.2Gbps	7Gbps	2.0Gbps
Bandwidth (per chip)	6.4Gbytes	28Gbytes	256Gbytes
Power Efficiency (Gbits per sec/pin)	1mW	-	0.33mW
Voltage	1.2V	1.35V, 1.5V	1.2V
Package Type	Discrete	Discrete	Si-Interposer



## Major Advantages of 2.5D + HBM

### High Performance/Bandwidth

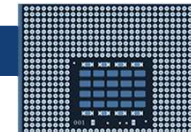
- Accelerate memory access, reduce processor idle times

### Lower Power

- HBM uses wide IO's that clock at lower frequencies and result in lower power consumption (~40% reduction)
- 2.5D memory placement is very close the core die (~70um vs. 2 cm. on a PCB)
  - → Smaller IO drivers are needed which reduce IO power

### Smaller Footprint due to integration / high packing density

- <50um micro-bump pitch for HBM memories can be accommodated on the silicon interposer providing high routing density (>5000 ubumps)
- Substantially smaller than DDR4/GDDR5
- Capable of signaling up to 2Gbps DDR between 4-5mm trace lengths



## 2.5D System

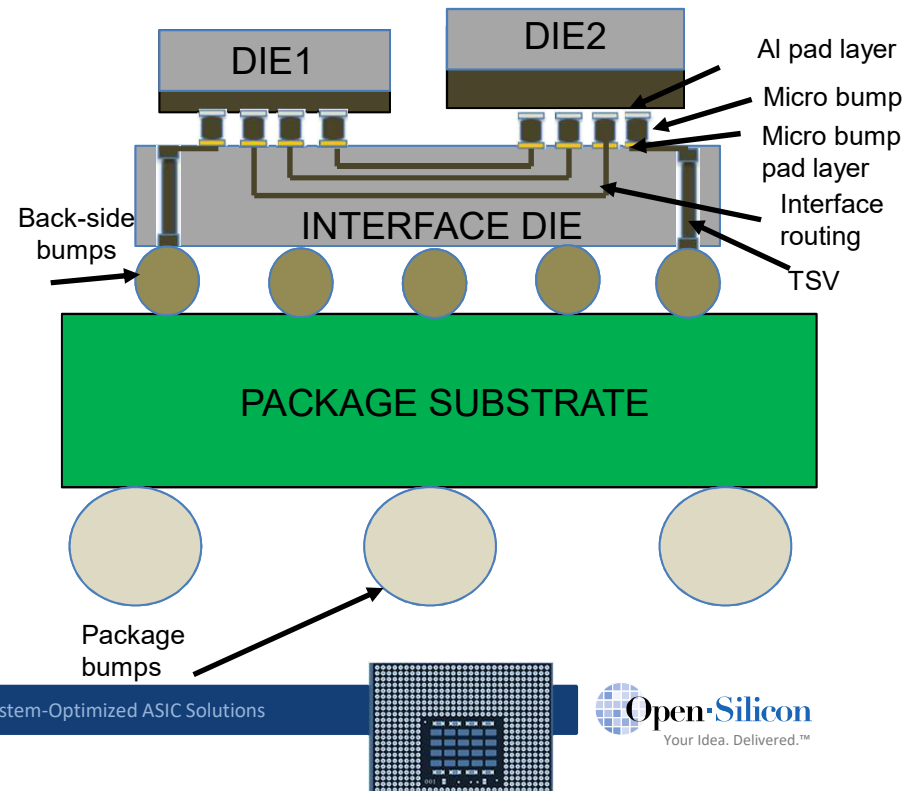
### 2.5D System Involves

- Mounting 2 or more Silicon DIEs onto an Interface DIE.
- Assembling the whole system into a single package.

### 2.5D System for High Performance Computing, Graphics, Network Applications

### 2.5D Systems Enable

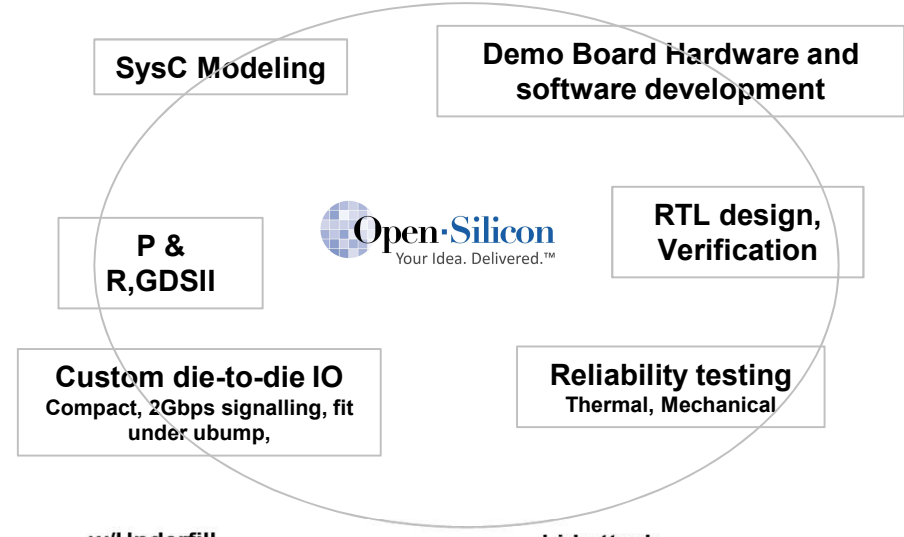
- Cost Reduction
- Lower Area
- Higher Bandwidth
- Lower Power
- Improved Yield due to Lower Area
- Heterogenous Integration etc



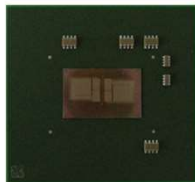
# Avatar 2.5D Solution Demonstration

First ASIC vendor to bring 2.5D to prototype silicon (Avatar). Awarded best chip design at ARM TechCon 2013, Santa Clara

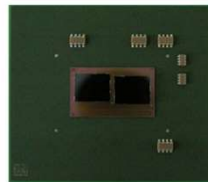
- Avatar logic die {
  - 2 dies of an ARM dual-core A9 SoC on 28nm process
- TSV Si Interposer {
  - “65-nm” 4 front-side, 1 back-side metal interposer
- Package Assembly {
  - Assemble 2 die on interposer, and placement on FlipChip package substrate
- High Level Goals {
  - Develop a complete 2.5D KGD solution
  - Demonstrate reusable portfolio of verified silicon dies with a higher level of chip abstraction



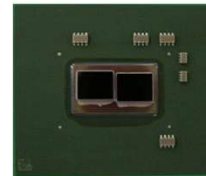
Interposer + Cap



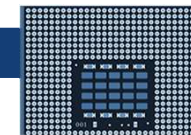
w/AVATAR



w/Underfill



Lid attach



## Components & Stakeholders Involved

**ASIC DIE**

- HBM2 PHY & I/O
- HBM2 Controller
- Manufacturing at a Foundry
- Micro-Bumping

*(Foundries like TSMC, GF etc or OSATs like ASE, Amkor etc)*

**HBM2 MEMORY DIE**

- SK Hynix, Samsung etc

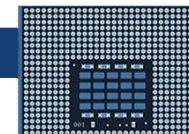
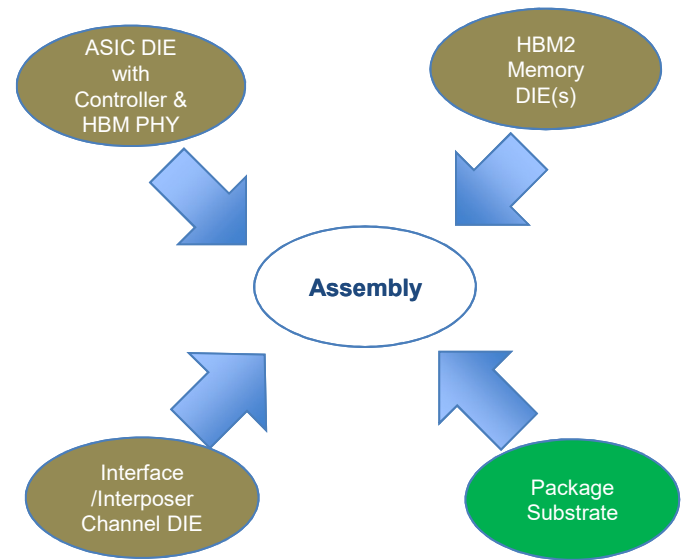
**Interposer DIE**

- Foundries like TSMC, GF, UMC etc
- Back-grinding and exposing TSVs, solder bumping (OSATs)

**Package Substrate**

**Assembly**

- OSATs (e.g. ASE)
- COWOS (TSMC)





## HBM2 Memory

Stacked DRAM with a base die

4H, 8H stack options

Up to 8GB memory density

8 independent channels to interface

Wide interface architecture for low power and high speed operation

Each channel has 128b data bus

IO voltage is 1.2V

Unterminated data/address/cmd/clk interfaces

DRAM core voltage is 1.2V independent of IO voltage

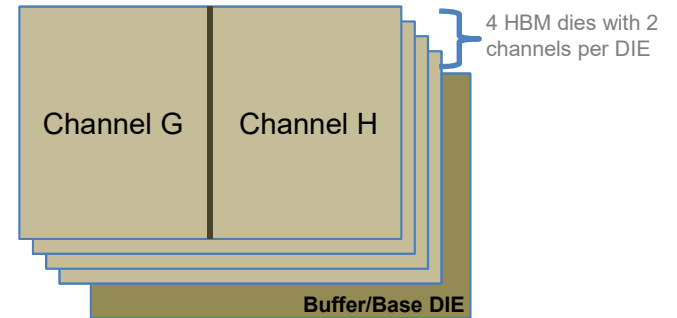
Base die has micro-bumps to connect to interface

~ 700 um high

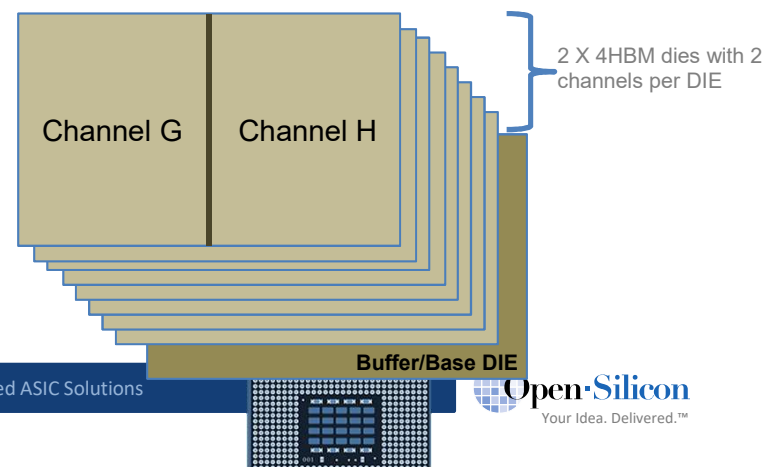
HBM2 targets 2Gbps data rates and higher

256 GBps bandwidth possible with 8H HBM2

### 4H HBM DIE

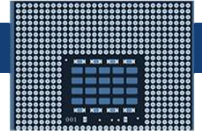
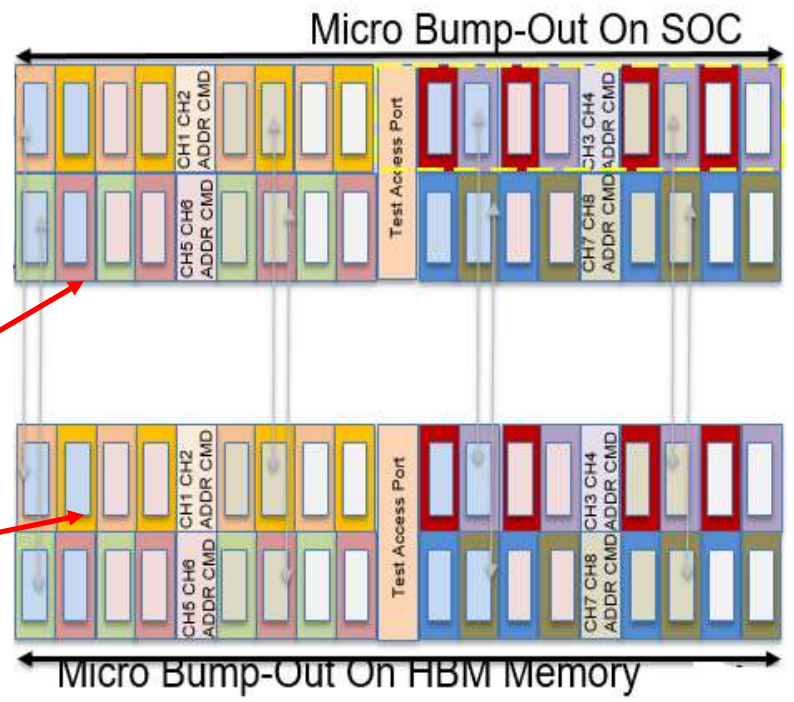
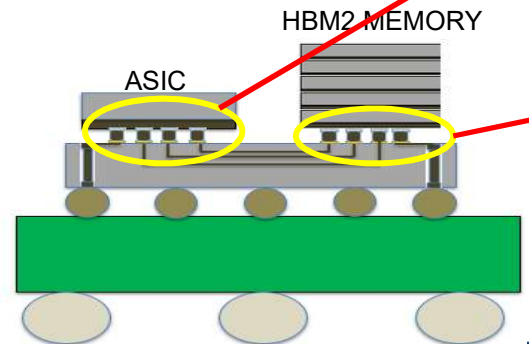


### 8H HBM DIE



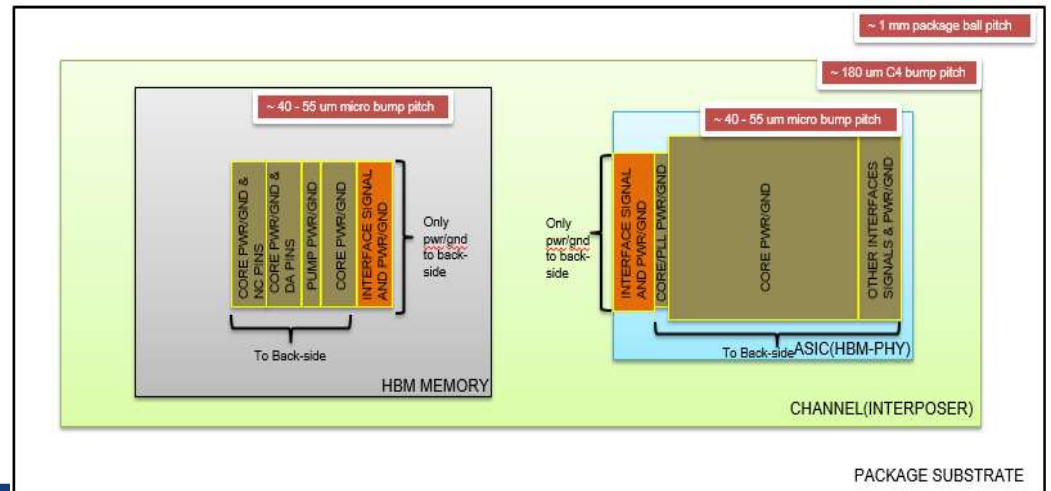
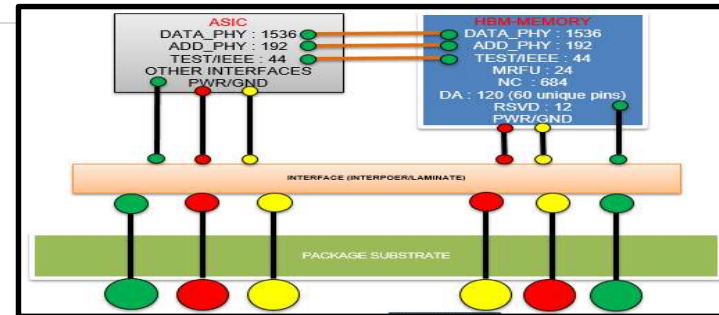
# ASIC Die: HBM2 Specific 2.5D System Connections

- 8 channels to interface through micro-bumps
- Micro-bumps at 55 um X 48 um pitch
- Interleaved channels
- Each channel has 212 signals
- Test access signals common to 8 channels
- Reset, temp, cattrip signals common
- All signals and power/gnd connections made using routing layers on interface DIE (interposer)



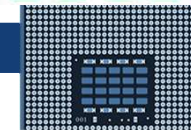
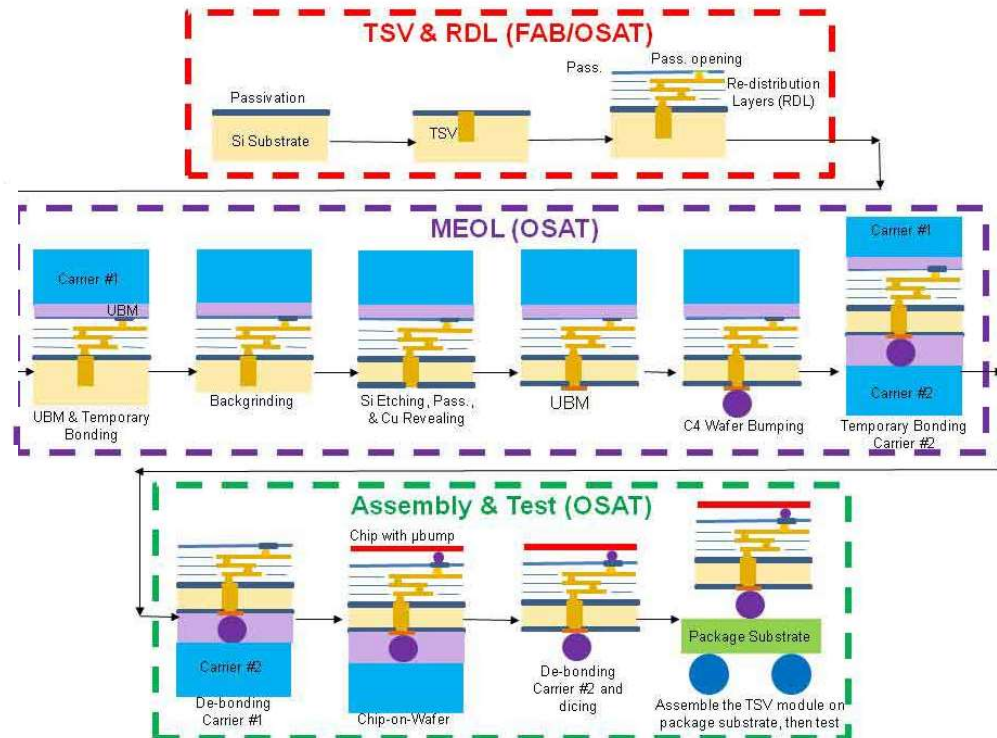
# ASIC Die and Interposer: 2.5D Requirements: Bump Design

- Micro-bump rules guided by bumping scheme
  - OSAT or Foundry
- Memory bumping scheme set by JEDEC
- PHY bump scheme guided by memory bumps
- Bump scheme to consider probe placement
- Back-side bumping on interposer for
  - ASIC pwr/gnd
  - Other ASIC interfaces
  - Memory pwr/gnd
  - Memory direct access
- Back-side bumping rules by assembly house
- Assignment to consider
  - Power delivery efficiency
  - Signal integrity
- TSV pitch guided by foundry



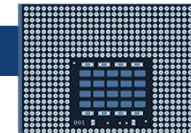
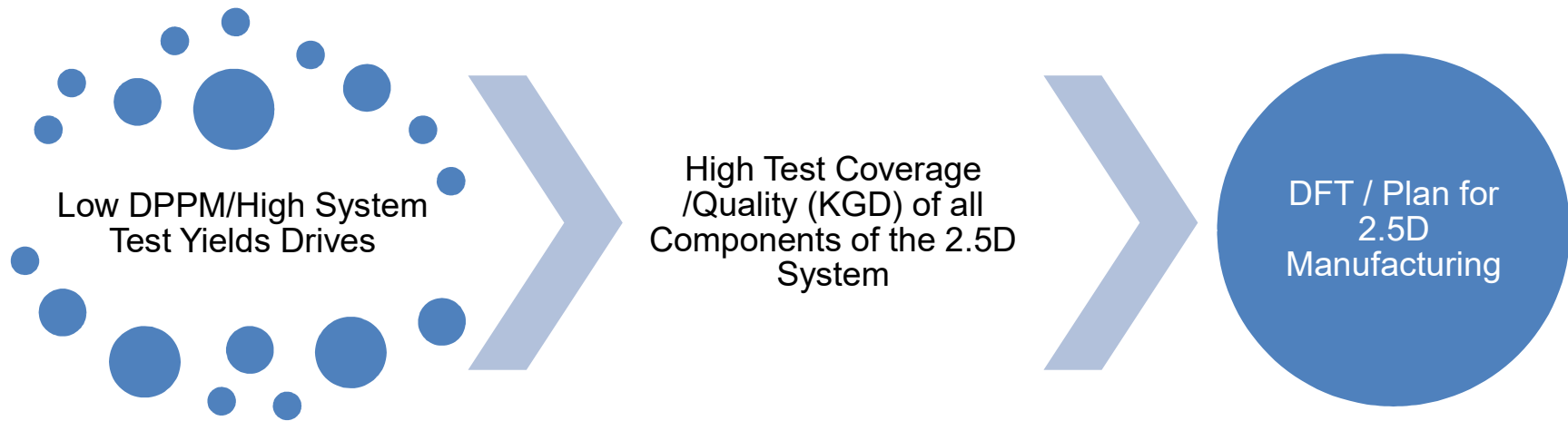
## 2.5D Package Assembly Flow (Typical)

- Interposer Manufacture
  - Fab, 65nm process
  - Additional TSV processes
- Interposer Preparation
  - Backgrind to 75-100um
  - Additional temporary bonding/de-bonding processes for carrier
- Package Assembly
  - Interposer attach to substrate
  - Die(s) attach to interposer
    - ✓ 40-60um pitch



## 2.5D System: Test / Fault Coverage Challenges

Low DPPM - >> Low System Level Fallout is Essential for Expensive Systems



## Test Coverage / KGD Plan for High System Yield/Low DPPM

### ASIC Die

- High speed probe testing (sacrificial probe test pads)
- Direct dock testing (at-speed)
- DFT with 98%+ fault coverage

### Interposer

- Test structures
  - Physical – Wafer coplanarity, optical surface inspections, TSV depth
  - Electrical – TSV leakage, metal pattern, via chain tests

### HBM Memory

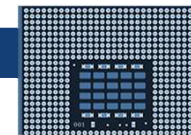
- KGD + wafer level burn-in (supplier proprietary)
- IEEE debug bus access

### Substrate

- Electrical tests
- Optical inspections

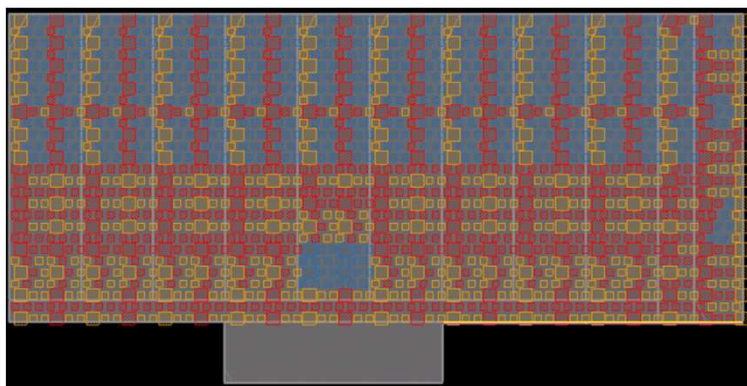


## 2.5D Test Flow

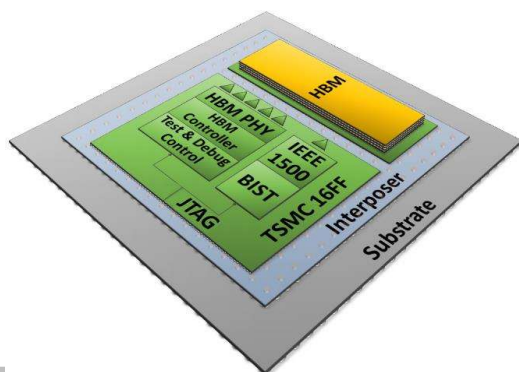




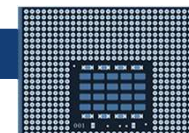
## Open-Silicon's Probing Scheme for 2.5D HBM2 ASIC SiP



- Signal uBump
- Gnd uBump
- Power uBump
- Gnd Probe-Pad
- Power Probe-Pad

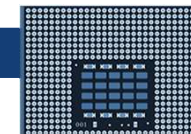
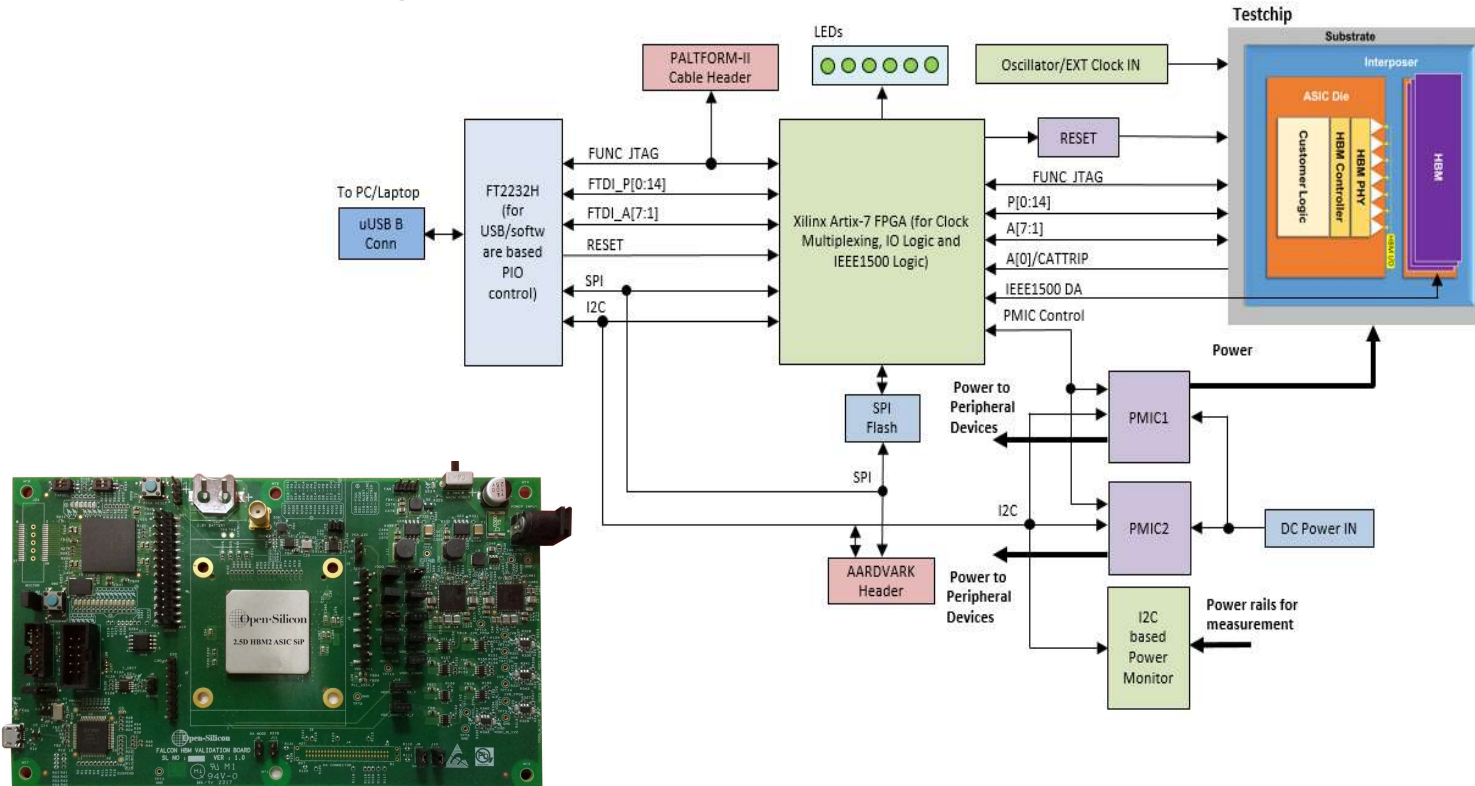


Testability feature deployed through probing mechanism for debug of ASIC SiPs with HBM memory embedded on a 2.5D interposer die





## 2.5D HBM2 ASIC SiP Validation/Evaluation Platform Reference Board Design



## Open-Silicon's 2.5D HBM2 ASIC SiP for Silicon Validation Parameters

ASIC Technology **16nm**

Interposer Technology :**65nm**

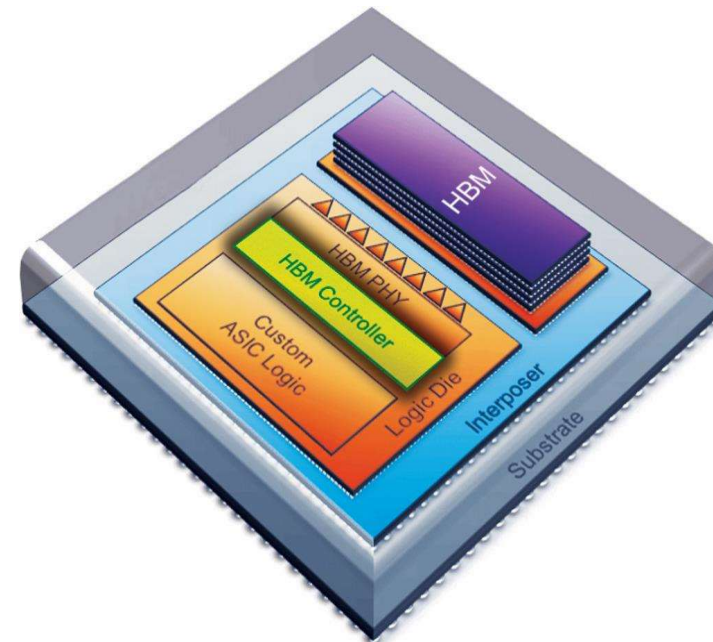
SiP Process :**CoWoS (2.5D)**

**HBM2 Memory**

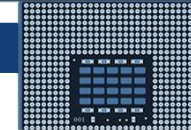
**Open-Silicon HBM2 IP Subsystem**

Core Voltage: **0.8V**

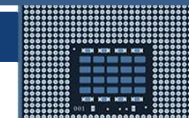
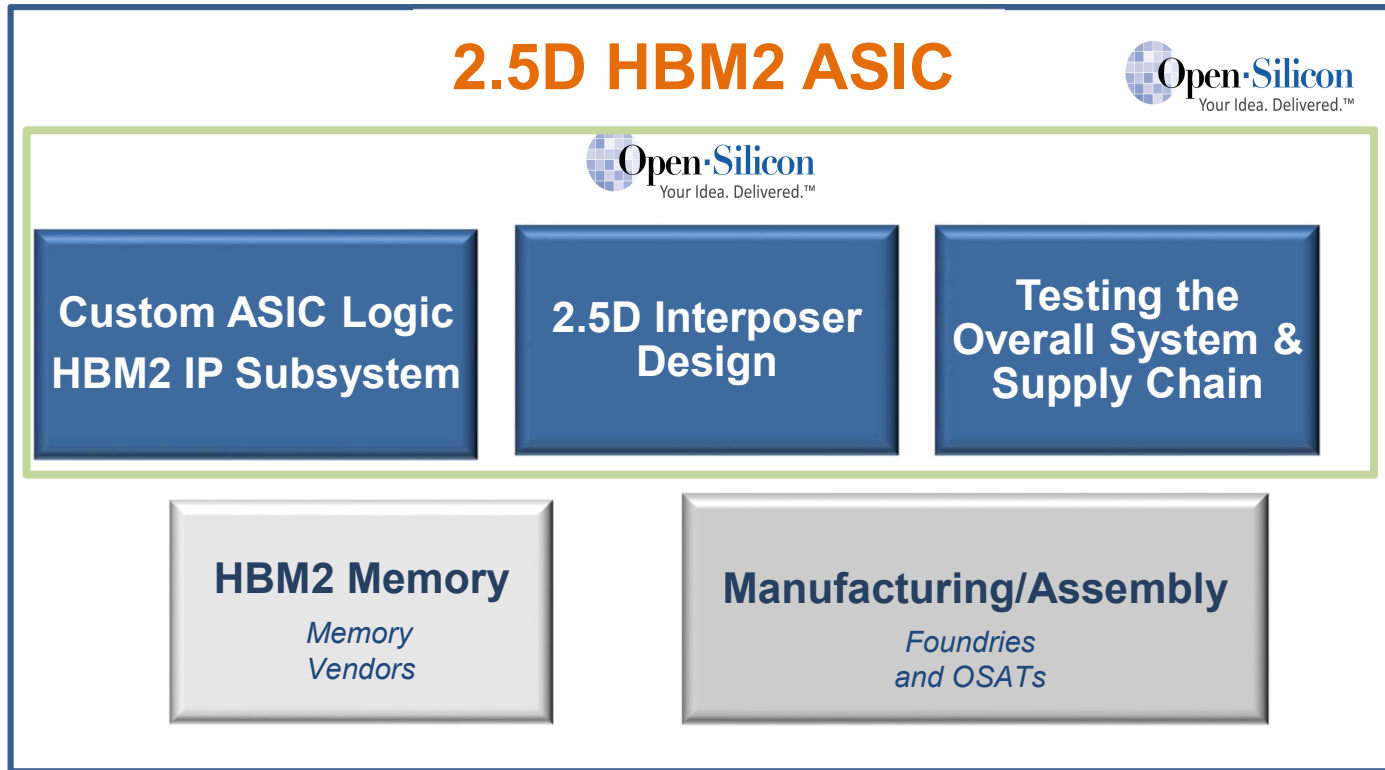
I/O Voltage : **1.2V**



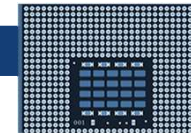
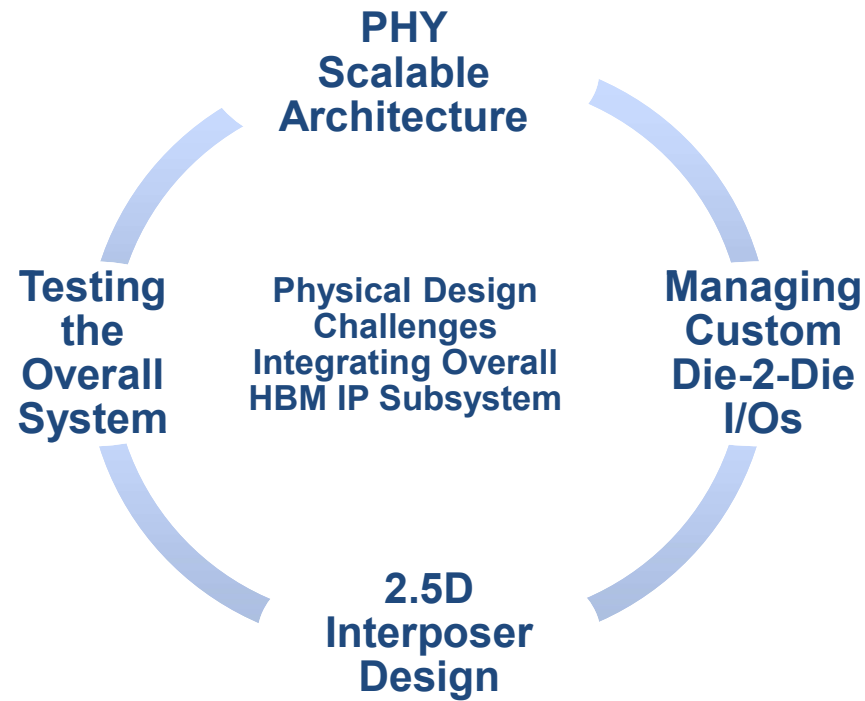
**This Platform Demonstrates**  
Open-Silicon HBM2 IP Subsystem ↔ HBM2 Die-Stack Interoperability



# Full Turnkey HBM2-Based 2.5D System Solution



## 2.5D HBM2 SiP Implementation Challenges



## 2.5D HBM2 SiP Manufacturing Challenges

### Foundries

- Microbumping,
- > Interposers exceeding reticle size (XL)
  - Reliability
  - Cost

### Interposer Foundries

- Keep costs low
- Optimize number of metal layers
- Integrate passives
- Test structures/DFT

### OSATs

- Low ESD environment
- Wafer level processing techniques
- Large stacked package reliability
  - Costs

### Semi's IP Houses Standard. Committees

- New additions and requirements (D2D IOs, ESD)
  - new players

### KGD Vendors

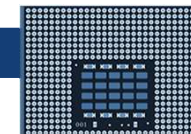
- Standards across suppliers on test/DFT, delivery metrics
- Heterogeneous integration

### DFT/Test

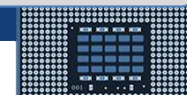
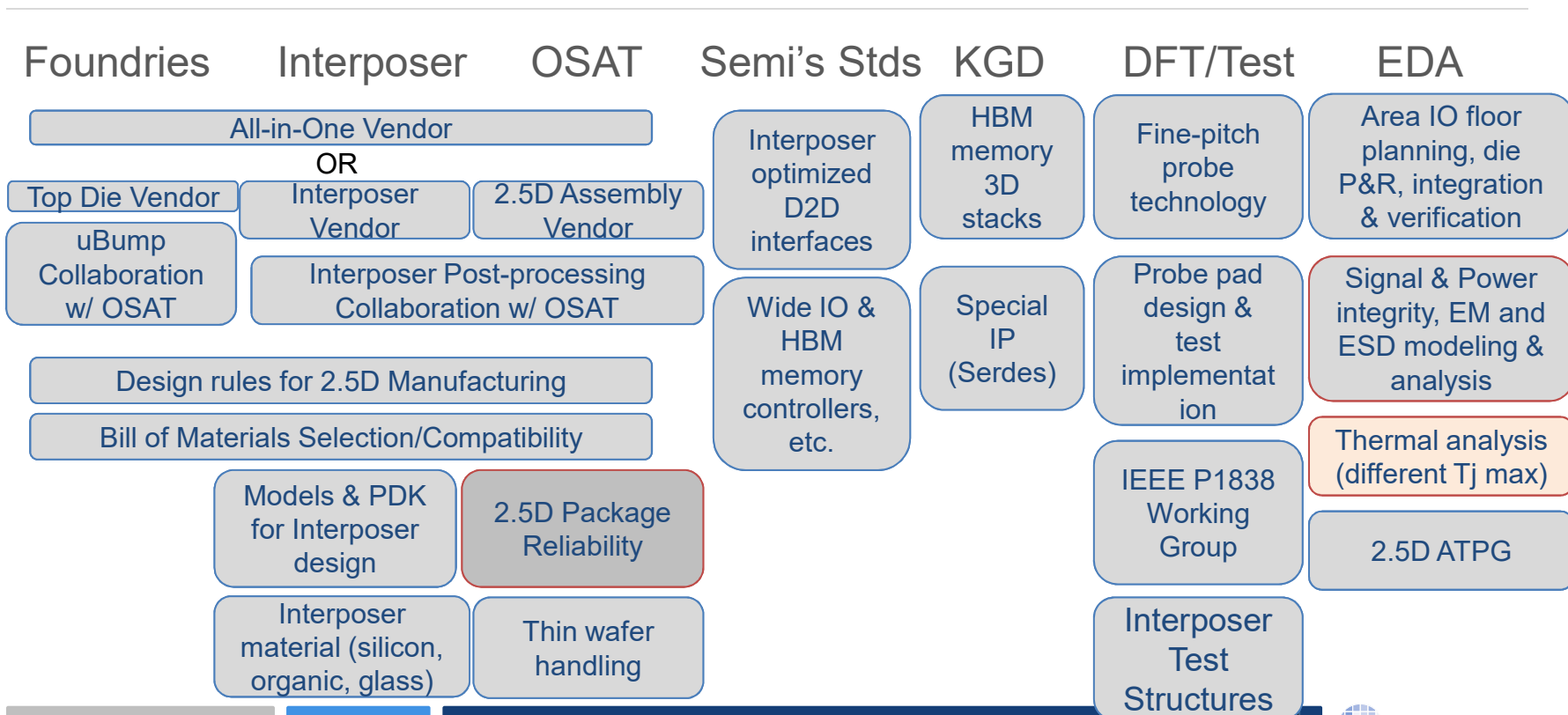
- Probing microbumps
- Testing out at many different levels
- High-speed testing at probe (direct dock)

### EDA

- Integrated tools connecting core die to interposer, package substrates



# Building the Ecosystem

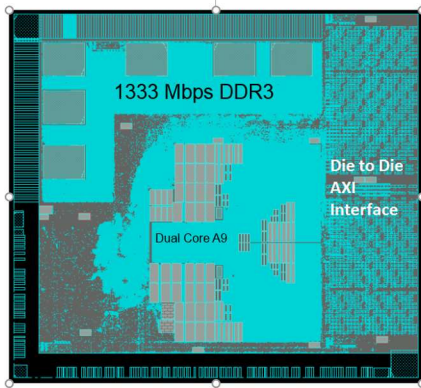




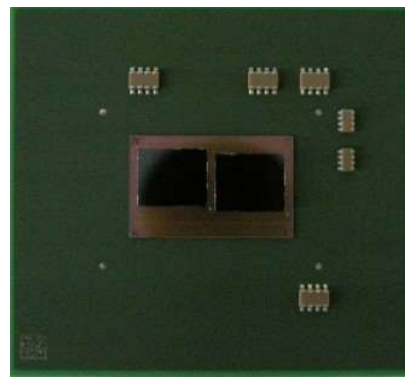
# Open-Silicon 2.5D and HBM2 Programs

*Proven Capability Across Foundries and OSATs*

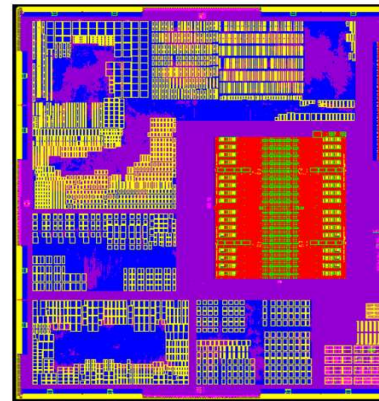
ASIC Die (GF 28nm)



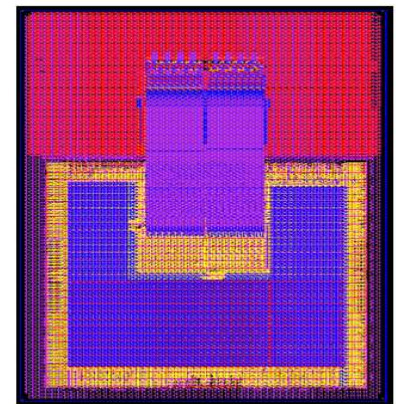
2.5D SiP



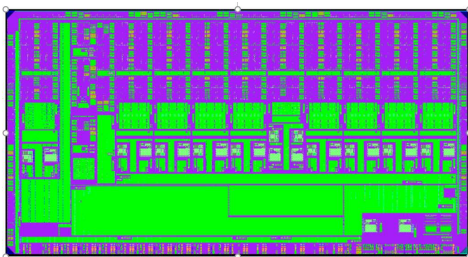
HBM2 ASIC Die (GF 55nm)



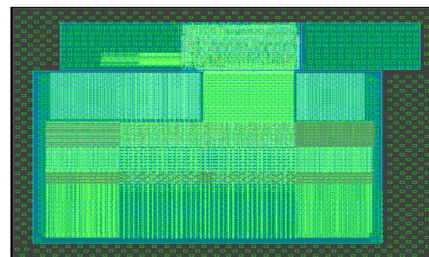
2.5D Interposer (GF 65nm)



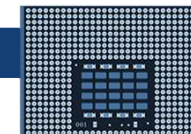
HBM2 ASIC Die (TSMC 16nm)



2.5D Interposer (TSMC 65nm)



HBM2 ASIC SiP (TSMC CoWoS)



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## Summary

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Multi die Integration for high performance ASICs is necessary

*We have hit the memory wall*

2.5D Integration of SoC with HBM memory is silicon proven

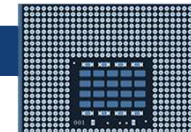
Result is major improvement in performance, lowering of power and reduced footprint

Silicon-proven HBM2 IP subsystem, design/manufacturing of HBM2 ASIC SiPs from a single vendor

*Lowers risk and time-to-market*

**HBM ecosystem is ready for high volume manufacturing of HBM2 ASIC SiPs**

---







THANK YOU

